



Conduction Immunity Test Result

Applicant :	APTCHIP MICROELECTRONICS CO., LTD				
Location:	The company is located in Shenzhen Nanshan District high tech Industrial Park (South) a high-tech South Wonderland North Block Building Room 301.				
EUT :	APT32F101 TOUCH KEY DEMO BOARD	Model Name :	APT32F101		
Temperature :	21.8°C	Relative Humidity :	52%		
Pressure :	100KPa	Test Date :	2017.07.27		
Test Mode :	WORKING	Test Power	AC240V/50HZ		
Test standard	<input type="checkbox"/> IEC 61000-4-6 <input checked="" type="checkbox"/> EN 61000-4-6 <input type="checkbox"/> other:				
Test Equipment: (1) Conduction Immunity GENERATOR / M/N: CDG-6000-25 126A1280/2014 (2) 6dB Attenuator ATT-6DB-100 A100W224 (3) CDN CDN-M2+3 A2210275/2014					
Performance Criterion:	A: Normal performance within limits specified by the manufacturer, request or purchaser B: Temporary loss of function or degradation of performance which ceases after the disturbance ceases, and from which the equipment under test recovers its normal performance, without operator intervention C: Temporary loss of function or degradation of performance, the correction of which requires operator intervention D: Loss of function or degradation of performance which is not recoverable, owing to damage to hardware or software, or loss of data				
Frequency Step:	1 %	Modulated Signal:	<input checked="" type="checkbox"/> AM 1KHz 80%	Performance Criterion	Result
Dwell Time:	3000 ms		<input type="checkbox"/> None		
Test Port	Frequency Range(MHz)	Applied Voltage (Vr.m.s.)		A	PASS
AC Mains	0.15-80	10			
D.C. Power Lines					
Control Line					
Signal Line					
Note: 试验中试验后 EUT 无异常。					



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Shenzhen STS Test Services Co., Ltd.

编 号: STS-E-05-06 Rev:A/0

Test Engineer:

Vyta. Hee